

<b>Notice of References Cited</b>	Application/Control No. 10/826,170		Applicant(s)/Patent Under Reexamination CRONIN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Developing using Crystallographic Maps" at <a href="http://www.ysbl.york.ac.uk/~cowtan/clipper/doc/p_develop_map.html">www.ysbl.york.ac.uk/~cowtan/clipper/doc/p_develop_map.html</a> , last viewed on 1/6/08
	V	Skarzynski et al., "Industrial perspective on X-ray data collection and analysis", Acta Crystallogr D Biol Crystallogr D62:102-107, 2006
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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